

# 100 MHz Differential Buffer for PCI Express and SATA

#### **Features**

- Two differential 0.7V clock output pairs
- OE# input for enabling SRC outputs
- Individual OE controls
- Low CTC jitter (< 50 ps)
- Spread Aware
- 3.3V operation
- Industrial Temperature Grade -40°C to +85°C
- 16-pin TSSOP package

## **Functional Description**

The SL28DB200 is a differential buffer capable of distributing the Serial Reference Clock (SRC) for PCI Express Gen2 and SATA implementations. The buffer enables the application system to control the distribution of the SRC.

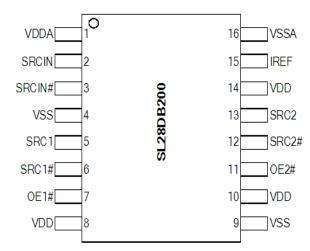
## **Applications**

- Network/Media Attached Storage
- Routers/IP Gateways
- Multi-function Printers

## **Block Diagram**

# OE1# OE2# Output Control Output Buffer SRC1 SRC1# SRC2 SRC1N#

# **Pin Configuration**



16 TSSOP



# **Pin Description**

Pin	Name	Type	Description
2,3	SRCIN, SRCIN#	I,DIF	0.7V Differential inputs
5,6,13,12	SRC[1:2], SRC[1:2]#	O,DIF	0.7V Differential Clock Outputs
7,11	OE[1:2]#	I,SE	3.3V LVTTL input for enabling differential outputs
15	IREF	I	A precision resistor 475 ohm is attached to this pin to set the differential output current
1	VDDA	PWR	3.3V Power Supply
16	VSSA	GND	Ground
8,10,14	VDD	PWR	3.3V power supply for outputs
4,9	VSS	GND	Ground for outputs

Notes: I=Input, O=Output, DIF=Differential signal, SE=Single Ended, PWR=Power input, GND=Ground

Table 1. Buffer Power-up State Machine

State	Description
S0	3.3V Buffer power off
S1	After 3.3V supply is detected to rise above 1.8V - 2.0V, the buffer enters state 1 and initiates a 0.2-ms–0.3-ms delay
S2	Buffer waits for a valid clock on the SRCIN input
S3	Once a valid input is detected, the buffer enters state 3 and enables outputs for normal operation

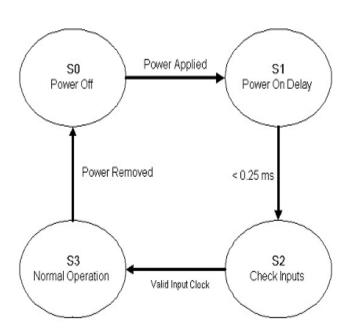


Figure 1. Buffer Power-up State Diagram



## **Output Enable Clarification**

OE# functionality allows for enabling and disabling individual outputs. OE1# and OE2# are Active LOW inputs. Disabling the outputs may be implemented by deasserting the OE# input pin. If the OE# pin is deasserted, the output of interest will be tri-stated. (The assertion and deassertion of this signal is absolutely asynchronous.)

#### **OE** Assertion

All differential outputs that were tri-stated will resume normal operation in a glitch-free manner. The maximum latency from the assertion to active outputs is between 2–6 SRC clock periods. In addition, SRC clocks will be driven high within 15 ns of OE# assertion to a voltage greater than 200 mV

#### **OE** Deassertion

The impact of deasserting OE# is that each corresponding output will transition from normal operation to tri-state in a glitch-free manner. The maximum latency from the deassertion to tri-stated outputs is between 2–6 DIF clock periods.

**Table 2. OE Functionality** 

OE#	SRC,SRC#
0	Enable
1	Tri-State

#### **Absolute Maximum Conditions**

Parameter	Description	Condition	Min.	Max.	Unit
VDD	Core Supply Voltage		-0.5	4.6	V
VDDA	Analog Supply Voltage		-0.5	4.6	V
V <sub>IN</sub>	Input Voltage	Relative to V <sub>SS</sub>	-0.5	V <sub>DD</sub> + 0.5	VDC
T <sub>S</sub>	Temperature, Storage	Non-functional	-65	+150	°C
T <sub>A</sub>	Temperature, Operating Ambient (Commercial Grade)	Functional	0	85	°C
T <sub>A</sub>	Temperature, Operating Ambient (Industrial Grade)	Functional	-40	85	°C
T <sub>J</sub>	Temperature, Junction	Functional		150	°C
ESD <sub>HBM</sub>	ESD Protection (Human Body Model)	JEDEC (JESD 22 - A114)	2000	_	V
UL-94	Flammability Rating	UL (Class)	V-0		
MSL	Moisture Sensitivity Level				

## **DC Electrical Specifications**

Parameter	Description	Condition	Min.	Max.	Unit
VDDA <sub>,</sub> VDD	3.3V Operating Voltage	$3.3 \pm 5\%$	3.135	3.465	V
$V_{IL}$	3.3V Input Low Voltage		$V_{SS} - 0.5$	0.8	V
$V_{IH}$	3.3V Input High Voltage		2.0	V <sub>DD</sub> + 0.5	V
I <sub>IL</sub>	Input Low Leakage Current	except internal pull-up resistors, 0 < V <sub>IN</sub> < V <sub>DD</sub>	<b>-</b> 5		μΑ
I <sub>IH</sub>	Input High Leakage Current	except internal pull-down resistors, $0 < V_{IN} < V_{DD}$		5	μΑ
C <sub>IN</sub>	Input Pin Capacitance		1.5	5	pF
C <sub>OUT</sub>	Output Pin Capacitance			6	pF
L <sub>IN</sub>	Pin Inductance		_	7	nΗ
I <sub>DD3.3V</sub>	Dynamic Supply Current	At max. load, Full Active, at 100MHz	_	60	mA



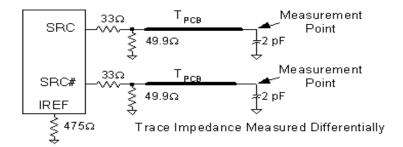
# **AC Electrical Specifications**

All measurements at VDD (typical) = 3.3V,  $T_A = 25$ °C unless otherwise stated

Parameter	Description Condition		Min.	Max.	Unit
SRCIN at 0	.7V				
T <sub>PERIOD</sub>	Average Period	Measured at crossing point V <sub>OX</sub>	9.9970	10.0533	ns
T <sub>ABSMIN-IN</sub>	Absolute minimum clock periods	Measured at crossing point V <sub>OX</sub>	9.8720		ns
T <sub>R</sub> / T <sub>F</sub>	SRC and SRC# Rise and Fall Times	Single ended measurement: $V_{OL} = 0.175$ to $V_{OH} = 0.525V$ (Averaged)	0.6	4	V/ns
$V_{IH}$	Differential Input High Voltage		150		mV
$V_{IL}$	Differential Input Low Voltage			-150	mV
V <sub>OX</sub>	Crossing Point Voltage at 0.7V Swing	Single-ended measurement	250	550	mV
$\Delta V_{OX}$	Vcross Variation over all edges	Single-ended measurement		140	mV
$V_{RB}$	Differential Ringback Voltage		-100	100	mV
T <sub>STABLE</sub>	Time before ringback allowed		500		ps
$V_{MAX}$	Absolute maximum input voltage			1.15	V
V <sub>MIN</sub>	Absolute minimum input voltage		-0.3		V
T <sub>DC</sub>	SRC and SRC# Duty Cycle	Measured at crossing point V <sub>OX</sub>	45	55	%
T <sub>RFM</sub>	Rise/Fall Matching	Determined as a fraction of $2*(T_R - T_F)/(T_R + T_F)$	_	20	%
SRC at 0.7	V			l	
F <sub>IN</sub>	Input Frequency		90	210	MHz
F <sub>ERROR</sub>	Input/Output Frequency Error		_	0	ppm
T <sub>DC</sub>	SRC and SRC# Duty Cycle	Measured at crossing point V <sub>OX</sub>	45	55	%
T <sub>PERIOD</sub>	Average Period	Measured at crossing point V <sub>OX</sub> at 100 MHz	9.9970	10.0533	ns
T <sub>R</sub> / T <sub>F</sub>	SRC[1:2] and SRC[1:2]# Rise and Fall Times	Single-ended measurement: $V_{OL} = 0.175$ to $V_{OH} = 0.525V$ (Averaged)	175	700	ps
T <sub>RFM</sub>	Rise/Fall Matching	Determined as a fraction of $2 * (T_R - T_F)/(T_R + T_F)$	_	20	%
$\Delta T_R / \Delta T_F$	Rise and Fall Time Variation Variation	Single-ended measurement: $V_{OL} = 0.175$ to $V_{OH} = 0.525V$ (Real Time)	_	125	ps
$V_{HIGH}$	Voltage High	Single-ended measurement	660	850	mv
$V_{LOW}$	Voltage Low	Single-ended measurement	-150	_	mv
$V_{OX}$	Crossing Point Voltage at 0.7V Swing	Single-ended measurement	250	550	mv
$\Delta V_{OX}$	Vcross Variation over all edges	Single-ended measurement	_	140	mV
V <sub>OVS</sub>	Maximum Overshoot Voltage	Single-ended measurement	_	V <sub>HIGH</sub> + 0.3	V
V <sub>UDS</sub>	Minimum Undershoot Voltage	Single-ended measurement	_	-0.3	V
V <sub>RB</sub>	Ring Back Voltage	Single-ended measurement	0.2	N/A	V
T <sub>CCJ</sub>	Cycle to Cycle Jitter	Jitter is additive	_	50	ps
T <sub>SKEW</sub>	Any SRC/SRC# to SRC/SRC# Clock Skew	Measured at crossing point V <sub>OX</sub>	-	50	ps
T <sub>PD</sub>	Input to output skew	Measured at crossing point V <sub>OX</sub>	2.5	4.5	ns



# **Test and Measurement Setup**



**Figure 1. Differential Clock Termination** 

# **Switching Waveforms**

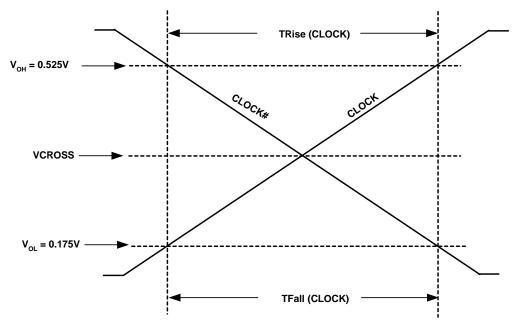


Figure 2. Single-Ended Measurement Points for TRise and TFall



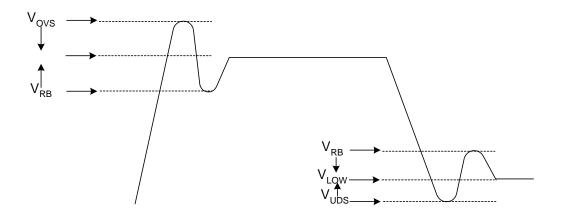


Figure 3. Single-ended Measurement Points for  $V_{\text{OVS}}$ ,  $V_{\text{UDS}}$  and  $V_{\text{RB}}$ 

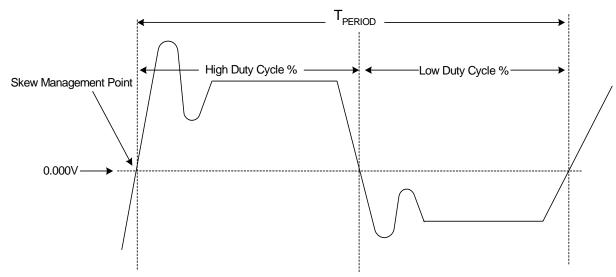


Figure 4. Differential (Clock-Clock#) Measurement Points (Tperiod, Duty Cycle and Jitter)

# **Ordering Information**

Ordering Code	Package Type	Operating Range	
Lead-free			
SL28DB200AZC	16-pin TSSOP	Commercial, 0°C to 85°C	
SL28DB200AZCT	16-pin TSSOP—(Tape and Reel)	Commercial, 0°C to 85°C	
SL28DB200AZI	16-pin TSSOP	Industrial, -40°C to 85°C	
SL28DB200AZIT	16-pin TSSOP—(Tape and Reel)	Industrial, -40°C to 85°C	

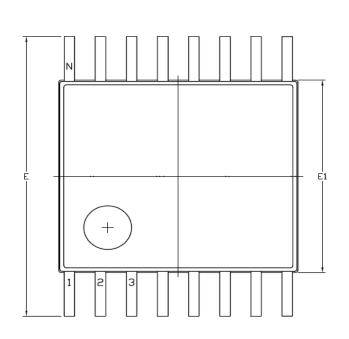
Note: All oderables are Lead-free and RoHS compliant

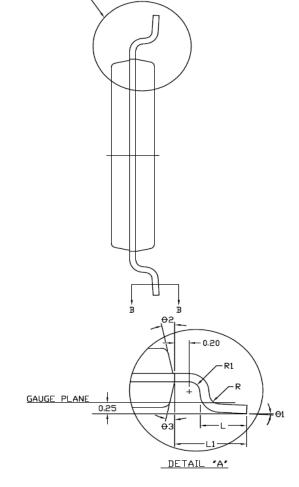


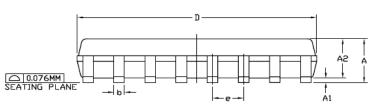
## **Package Drawing and Dimensions**

#### 16-Lead Thin Shrunk Small Outline Package

SEE DETAIL 'A'-







SYMB□L	DIMEN	NDIS	IN MM	DIMEN	SION I	N INCH
SIMBUL	MIN.	N□M.	MAX.	MIN.	N□M.	MAX.
Α			1.20			.047
A1	0.05		0.15	.002		.006
A2	0.80	0.90	1.05	.031	.035	.041
b	0.19		0.30	.007		.012
b1	0.19	0.22	0.25	.007	.009	.010
c	0.09		0.20	.004		.008
⊂1	0.09		0.16	.004		.006
D	4.90	5.00	5.10	.193	.197	.200
е	0.	65 BS	C.	.026 BSC		
E	6.	40 BS	C.	.252 BSC.		
E1	4.30	4.40	4.50	.169	.173	.177
L	0.50	0.60	0.75	.020	.024	.030
∟1	1.	00 REF	₹.	.039 REF.		₹.
R	0.09			.004		
R1	0.09			.004		
<del>0</del> 1	0		8	0		8
92	12 REF.			12 REF.		
<del>0</del> 3	12 REF.			1	2 REF	

<u> </u>	—b—	<u> </u>			
c		⊂1			
Ŧ	b1	1			
SECTION B-B					

#### NDTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSION 'D' DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 PER SIDE.
- 3. DIMENSION 'E1' DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION, INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 PER SIDE.
- 4. "N" IS THE NUMBER OF TERMINAL POSITIONS.
- 5. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- 6. REFERENCE DRAWING JEDEC MD-153, VARIATION AB.



## **Document History Page**

Document Title: SL28DB200 PCI Express Gen2 and SATA Differential Buffer Document #: 38-07722 Rev *C						
REV.	REV.   ECR#   Issue Date   Orig. of Change   Description of Change					
1.0		06/17/10	TRP	Initial Release		
AA		09/27/10	TRP	Updated Dynamic Supply Current		

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